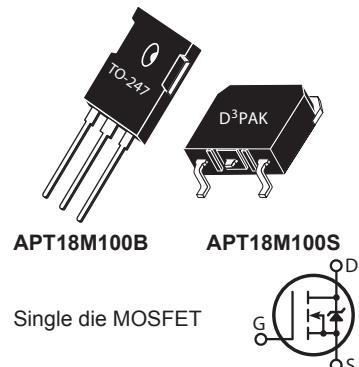


## N-Channel MOSFET

Power MOS 8™ is a high speed, high voltage N-channel switch-mode power MOSFET. A proprietary planar stripe design yields excellent reliability and manufacturability. Low switching loss is achieved with low input capacitance and ultra low  $C_{rss}$  "Miller" capacitance. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control slew rates during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency. Reliability in flyback, boost, forward, and other circuits is enhanced by the high avalanche energy capability.



### FEATURES

- Fast switching with low EMI/RFI
- Low  $R_{DS(on)}$
- Ultra low  $C_{rss}$  for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant 

### TYPICAL APPLICATIONS

- PFC and other boost converter
- Buck converter
- Two switch forward (asymmetrical bridge)
- Single switch forward
- Flyback
- Inverters

### Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
$I_D$	Continuous Drain Current @ $T_C = 25^\circ\text{C}$	18	A
	Continuous Drain Current @ $T_C = 100^\circ\text{C}$	12	
$I_{DM}$	Pulsed Drain Current <sup>①</sup>	68	
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy <sup>②</sup>	1070	mJ
$I_{AR}$	Avalanche Current, Repetitive or Non-Repetitive	9	A

### Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Typ	Max	Unit
$P_D$	Total Power Dissipation @ $T_C = 25^\circ\text{C}$			625	W
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.20	°C/W
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11		
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55		150	°C
$T_L$	Soldering Temperature for 10 Seconds (1.6mm from case)			300	
$W_T$	Package Weight		0.22		oz
			6.2		g
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in-lbf
				1.1	N·m

## Static Characteristics

$T_J = 25^\circ\text{C}$  unless otherwise specified

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Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$V_{BR(DSS)}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	1000			V
$\Delta V_{BR(DSS)}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}, I_D = 250\mu\text{A}$		1.15		$\text{V}/^\circ\text{C}$
$R_{DS(on)}$	Drain-Source On Resistance <sup>③</sup>	$V_{GS} = 10V, I_D = 9\text{A}$		0.60	0.70	$\Omega$
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 1\text{mA}$	3	4	5	V
$\Delta V_{GS(th)}/\Delta T_J$	Threshold Voltage Temperature Coefficient			-10		$\text{mV}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 1000\text{V}$	$T_J = 25^\circ\text{C}$		100	$\mu\text{A}$
		$V_{GS} = 0V$	$T_J = 125^\circ\text{C}$		500	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS} = \pm 30\text{V}$			$\pm 100$	nA

## Dynamic Characteristics

$T_J = 25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$g_{fs}$	Forward Transconductance	$V_{DS} = 50\text{V}, I_D = 9\text{A}$		19		S
$C_{iss}$	Input Capacitance	$V_{GS} = 0V, V_{DS} = 25\text{V}$ $f = 1\text{MHz}$		4845		$\text{pF}$
$C_{rss}$	Reverse Transfer Capacitance			65		
$C_{oss}$	Output Capacitance			405		
$C_{o(cr)}^{\text{④}}$	Effective Output Capacitance, Charge Related	$V_{GS} = 0V, V_{DS} = 0\text{V to } 667\text{V}$		165		$\text{pF}$
$C_{o(er)}^{\text{⑤}}$	Effective Output Capacitance, Energy Related			85		
$Q_g$	Total Gate Charge	$V_{GS} = 0\text{ to } 10\text{V}, I_D = 9\text{A},$ $V_{DS} = 500\text{V}$		150		$\text{nC}$
$Q_{gs}$	Gate-Source Charge			26		
$Q_{gd}$	Gate-Drain Charge			70		
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 667\text{V}, I_D = 9\text{A}$ $R_G = 4.7\Omega^{\text{⑥}}$ , $V_{GG} = 15\text{V}$		22		$\text{ns}$
$t_r$	Current Rise Time			20		
$t_{d(off)}$	Turn-Off Delay Time			75		
$t_f$	Current Fall Time			19		

## Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$I_s$	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n junction diode (body diode)			18	A
$I_{SM}$	Pulsed Source Current (Body Diode) <sup>①</sup>				68	
$V_{SD}$	Diode Forward Voltage	$I_{SD} = 9\text{A}, T_J = 25^\circ\text{C}, V_{GS} = 0\text{V}$			1.0	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 9\text{A}^{\text{③}}$ $di_{SD}/dt = 100\text{A}/\mu\text{s}, T_J = 25^\circ\text{C}$		1080		ns
$Q_{rr}$	Reverse Recovery Charge			24		
$dv/dt$	Peak Recovery $dv/dt$	$I_{SD} \leq 9\text{A}, di/dt \leq 1000\text{A}/\mu\text{s}, V_{DD} = 800\text{V}, T_J = 125^\circ\text{C}$			10	V/ns

① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

② Starting at  $T_J = 25^\circ\text{C}$ ,  $L = 26.42\text{mH}$ ,  $R_G = 4.7\Omega$ ,  $I_{AS} = 9\text{A}$ .

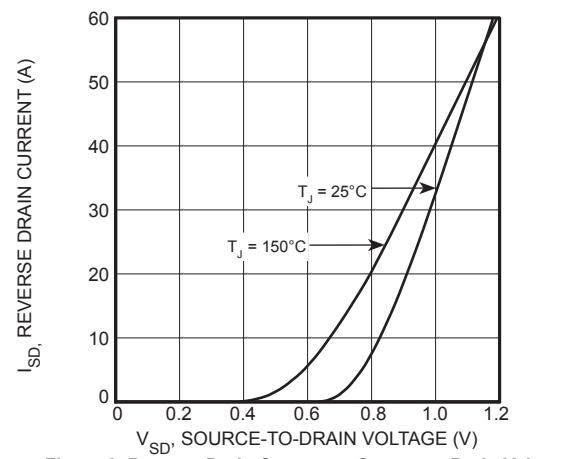
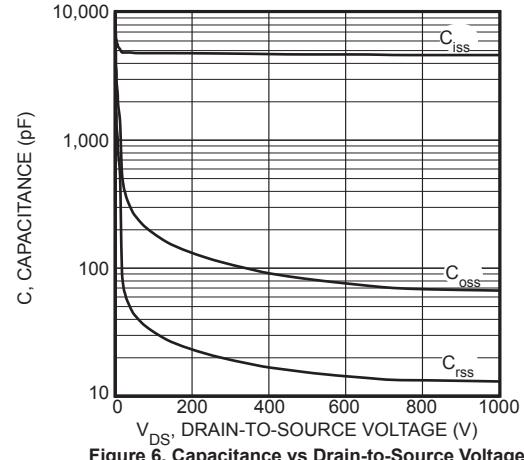
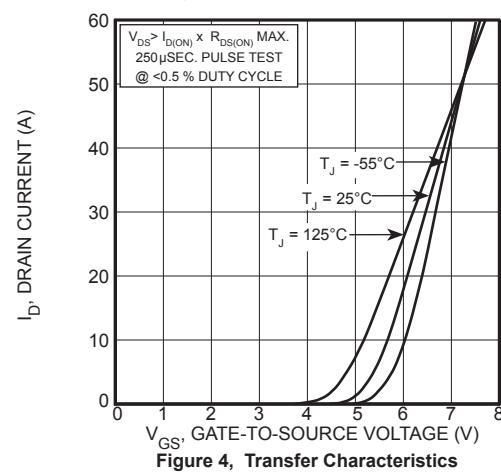
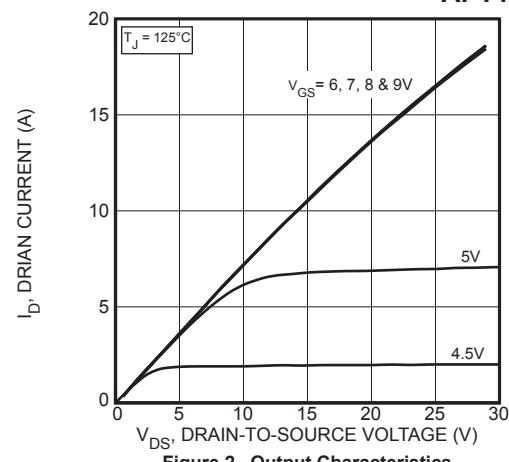
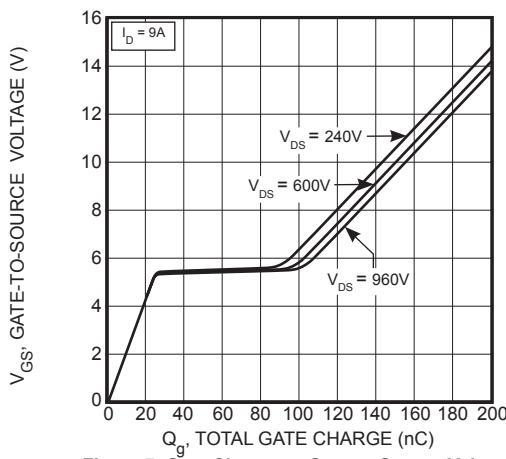
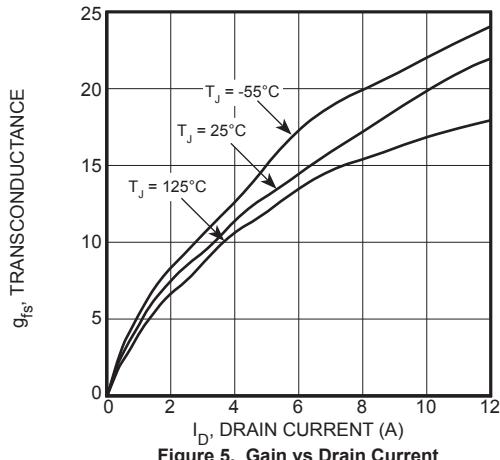
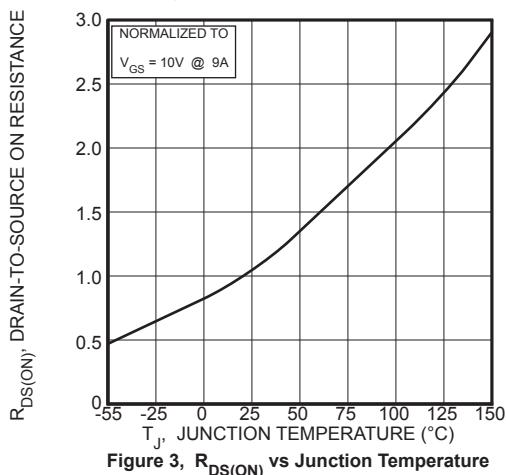
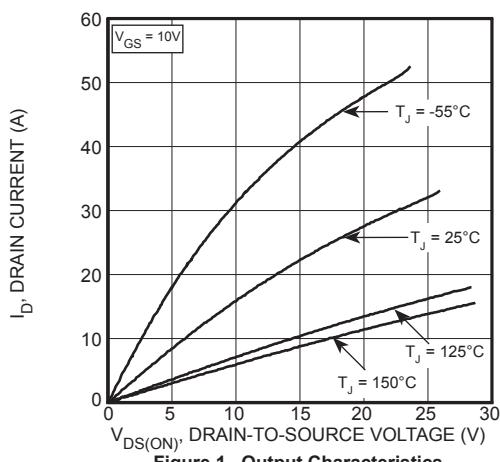
③ Pulse test: Pulse Width < 380μs, duty cycle < 2%.

④  $C_{o(cr)}$  is defined as a fixed capacitance with the same stored charge as  $C_{oss}$  with  $V_{DS} = 67\%$  of  $V_{(BR)DSS}$ .

⑤  $C_{o(er)}$  is defined as a fixed capacitance with the same stored energy as  $C_{oss}$  with  $V_{DS} = 67\%$  of  $V_{(BR)DSS}$ . To calculate  $C_{o(er)}$  for any value of  $V_{DS}$  less than  $V_{(BR)DSS}$ , use this equation:  $C_{o(er)} = -1.41E-8/V_{DS}^2 + 2.48E-9/V_{DS} + 4.81E-11$ .

⑥  $R_G$  is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



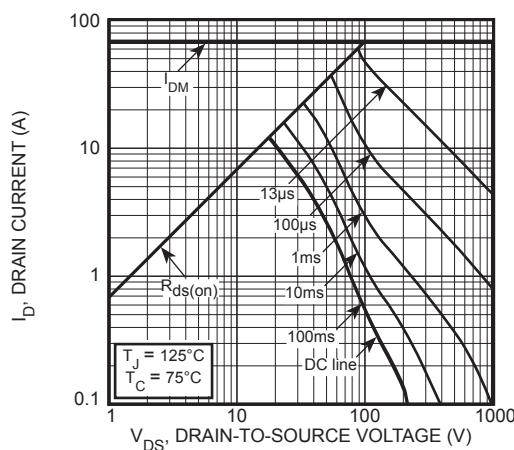
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Figure 9, Forward Safe Operating Area

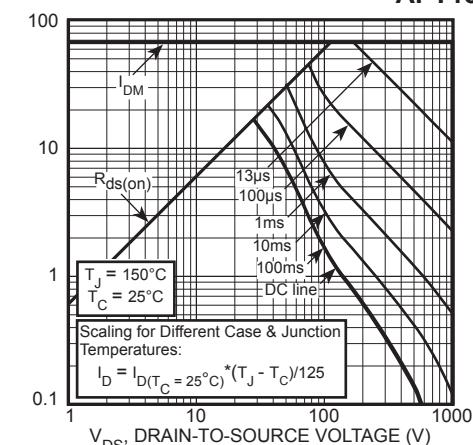


Figure 10, Maximum Forward Safe Operating Area

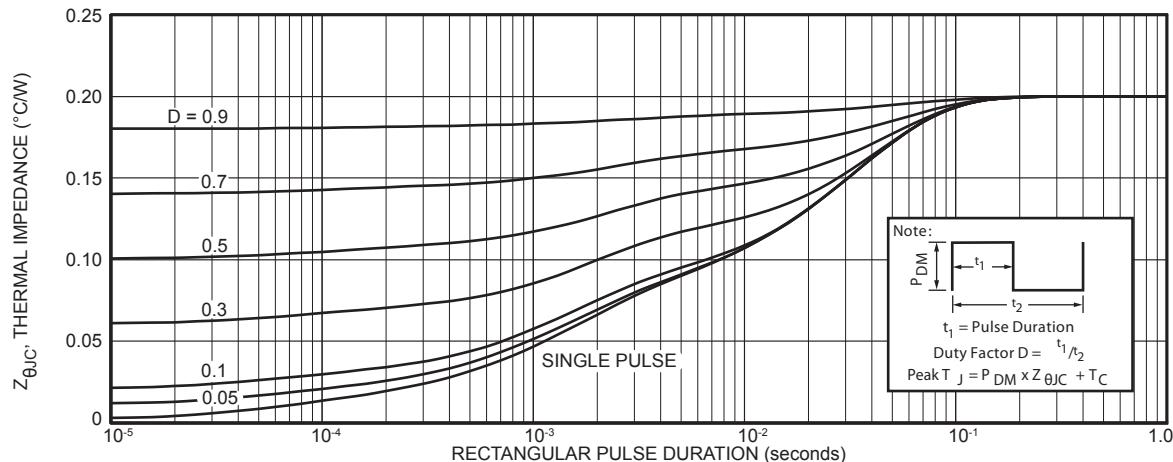
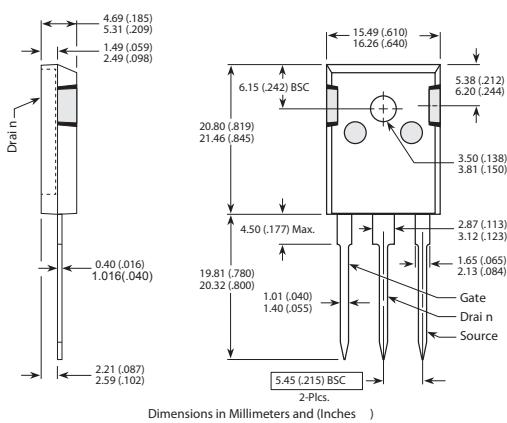


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

**TO-247 (B) Package Outline****e3 100% Sn Plated**